

Notice of References Cited	Application/Control No. 10/757,584	Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner William L. Boddie	Art Unit 2629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,171,978	12-1992	Mimlitch et al.	345/167
*	C	US-6,518,890	02-2003	Hallen et al.	340/691.7
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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